

January 2006

## FDD5810

# N-Channel PowerTrench<sup>®</sup> MOSFET 60V, 35A, 27m $\Omega$

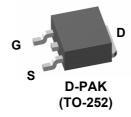
#### **Features**

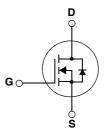
- $R_{DS(ON)} = 20.5 \text{m}\Omega$  (Typ.),  $V_{GS} = 5V$ ,  $I_D = 35A$
- $Q_{g(5)} = 13nC \text{ (Typ.)}, V_{GS} = 5V$
- Low Miller Charge
- Low Q<sub>rr</sub> Body Diode
- UIS Capability (Single Pulse / Repetitive Pulse)
- Qualified to AEC Q101
- RoHS Compliant

# **Applications**

- Motor / Body Load Control
- ABS Systems
- Powertrain Management
- Injection System
- DC-DC converters and Off-line UPS
- Distributed Power Architecture and VRMs
- Primary Switch for 12V and 24V systems







Symbol	Parameter		Ratings	Units
$V_{DSS}$	Drain to Source Voltage		60	V
V <sub>GS</sub>	Gate to Source Voltage		±20	V
	Drain Current Continuous (V <sub>GS</sub> = 10V, T <sub>C</sub> = 52°C)	(Note 1)	35	А
$I_D$	Drain Current Continuous (V <sub>GS</sub> = 5V, T <sub>C</sub> = 42°C)	(Note 1)	35	Α
	Continuous ( $T_A = 25^{\circ}C$ , $V_{GS} = 10V$ , with $R_{\theta JA} = 52^{\circ}C/W$ )		7.7	Α
	Pulsed		Figure 4	Α
E <sub>AS</sub>	Single Pulse Avalanche Energy (Note 2)		45	mJ
	Power Dissipation		88	W
$P_{D}$	Derate above 25°C		0.59	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature		-55 to 175	°C

### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance Junction to Case TO-252	1.7	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-252, 1in <sup>2</sup> copper pad area	52	°C/W

# **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD5810	FDD5810	TO-252AA	13"	12mm	2500 units

# **Electrical Characteristics** $T_J = 25$ °C unless otherwise noted

Parameter	lest Co	onditions	Min	Тур	Max	Units
cteristics						
Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_C$	as = 0V	60	-	-	V
Zara Cata Valtaga Drain Current	$V_{DS} = 48V$		-	-	1	^
Zero Gate Voltage Drain Current	$V_{GS} = 0V$	$T_{\rm C} = 150^{\rm o}{\rm C}$	-	-	250	μΑ
Gate to Source Leakage Current	$V_{GS} = \pm 20V$	•	-	-	±100	nA
	Cteristics Drain to Source Breakdown Voltage Zero Gate Voltage Drain Current					

#### On Characteristics

V <sub>GS(TH)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1	1.6	2	V
R <sub>DS(ON)</sub>	Drain to Source On Resistance	$I_D = 35A, V_{GS} = 10V$	-	16.5	20	
		$I_D = 35A, V_{GS} = 5V$	-	20.5	27	mΩ
		$I_D = 35A, V_{GS} = 10V,$ $T_J = 175^{\circ}C$	-	39	48	11152

### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 25V V 2V	-	1420	1890	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0V, f = 1MHz	-	150	200	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 111112	-	65	100	pF
R <sub>G</sub>	Gate Resistance	f = 1MHz	-	3.5	-	Ω
$Q_g$	Total Gate Charge at 10V	V <sub>GS</sub> = 0V to 10V	-	24	34	nC
$Q_g$	Total Gate Charge at 5V	V <sub>GS</sub> = 0V to 5V	-	13	18	nC
$Q_{g(th)}$	Threshold Gate Charge	$V_{GS} = 0V \text{ to } 1V$ $V_{DD} = 30V$ $I_{D} = 35A$	-	1.3	-	nC
$Q_{gs}$	Gate to Source Gate Charge	ID = 33A	-	4.0	-	nC
Q <sub>gs2</sub>	Gate Charge Threshold to Plateau		-	2.7	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge		-	5.0	-	nC

Switching Characteristics							
t <sub>on</sub>	Turn-On Time		-	-	130	ns	
t <sub>d(on)</sub>	Turn-On Delay Time		-	12	-	ns	
t <sub>r</sub>	Rise Time	$V_{DD} = 30V, I_{D} = 35A$	-	75	-	ns	
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{DD} = 30V, I_D = 35A$ $V_{GS} = 5V, R_{GS} = 11\Omega$	-	26	-	ns	
t <sub>f</sub>	Fall Time		-	34	-	ns	
t <sub>off</sub>	Turn-Off Time		-	-	90	ns	

### **Drain-Source Diode Characteristics**

V <sub>SD</sub>	I Source to Drain Diode Voltage F	I <sub>SD</sub> = 35A	-	-	1.25	V
		I <sub>SD</sub> = 16A	-	-	1.0	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = 35A, di/dt = 100A/μs	-	-	39	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$I_F = 35A$ , di/dt = 100A/ $\mu$ s	-	-	35	nC

Notes: 1: Package Limitation is 35A. 2: Starting  $T_J=25^{\circ}C$ ,  $L=110\mu H$ ,  $I_{AS}=28A$ ,  $V_{DD}=54V$ ,  $V_{GS}=10V$ .

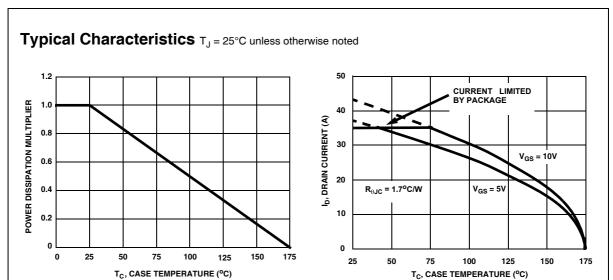


Figure 1. Normalized Power Dissipation vs Case Temperature

Figure 2. Maximum Continuous Drain Current vs Case Temperature

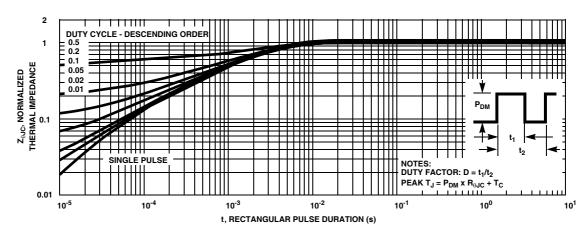


Figure 3. Normalized Maximum Transient Thermal Impedance

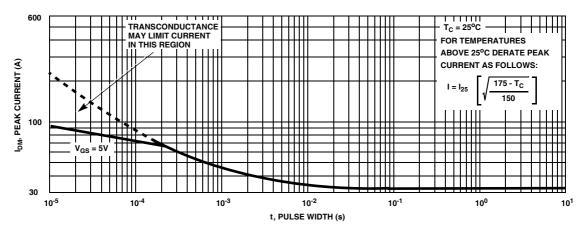
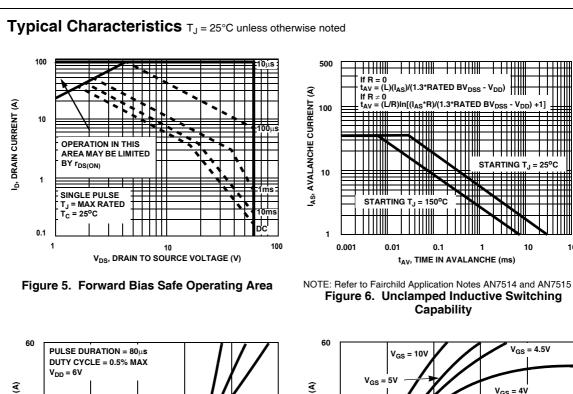


Figure 4. Peak Current Capability



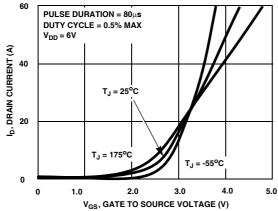


Figure 7. Transfer Characteristics

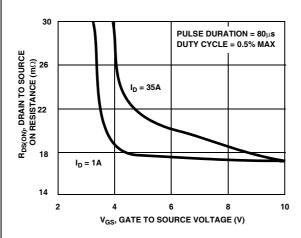


Figure 9. Drain to Source On Resistance vs Gate Voltage and Drain Current

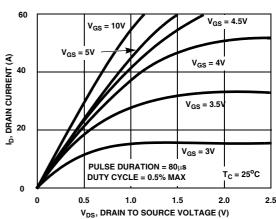


Figure 8. Saturation Characteristics

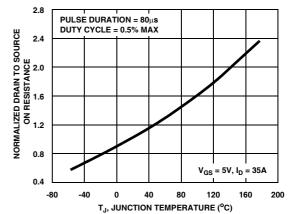
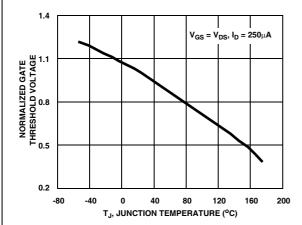


Figure 10. Normalized Drain to Source On Resistance vs Junction Temperature



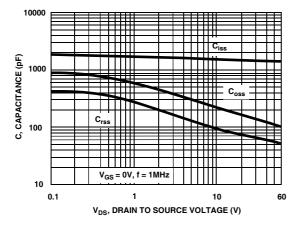


NORMALIZED DRAIN TO SOUNCE DR

1.2

Figure 11. Normalized Gate Threshold Voltage vs Junction Temperature

Figure 12. Normalized Drain to Source Breakdown Voltage vs Junction Temperature



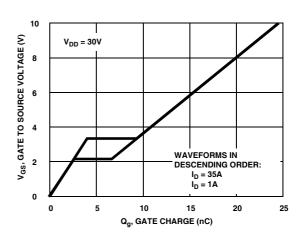


Figure 13. Capacitance vs Drain to Source Voltage

Figure 14. Gate Charge Waveforms for Constant Gate Current

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